

<b>Notice of References Cited</b>	Application/Control No. 10/562,795		Applicant(s)/Patent Under Reexamination SATO ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,870,355 A	02-1999	Fujihara, Shinobu	369/30.26
*	B	US-5,986,980 A	11-1999	Takeshita et al.	369/30.23
*	C	US-6,412,042 B1	06-2002	Paterson et al.	711/112
*	D	US-2002/0172104 A1	11-2002	Kaji, Toshihiko	369/30.11
*	E	US-2004/0001397 A1	01-2004	Jeong et al.	369/30.11
*	F	US-2004/0062154 A1	04-2004	Katsuki, Hideaki	369/030.07
*	G	US-2004/0264322 A1	12-2004	Shishido et al.	369/047.22
*	H	US-2005/0025015 A1	02-2005	Horibata, Yoshihiro	369/053.3
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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